

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET N 32120.CON.1		SERIAL NO. 10/014,310		
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Aro	AA	4,619,695	10/86	Oikawa et al				 -	
Aro	AB	5,772,860	06/98	Sawada et al		_	_		
ALD	AC	5,993,621	11/99	Liu		_	_		
Avo	AD	5,798,005	08/98	Murata et al			_		
ALO	AE	5,282,946	02/94	Kinoshita et al			- 4		
Aio	AF	5,993,575	11/99	Lo et al		_	_		
ALO	AG	5,809,393	09/98	Dunlop et al			_		
Aro	АН	5,780,755	07/98	Dunlop		_	_		
Aro	AI	5,468,401	11/95	Lum					
Aro	· AJ	5,087,297	02/92	Pouliquen		_			
Azo	. AK	5,693,203	12/97	Ohhashi			_		
ALO	AL	5,400,633	03/95	Segal		_	-		
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APPLICANT Ritesh P. Shah

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Ano	AA	590 904	04/1994	EPO	C23C	14/34		
Aro	AB	6264232	09/1994	Japan	-		X	
A10	AC	8 269701	10/1996	Japan			Х	
Aro	AD.	8 232061	06/1996	Japan			X	
Avo	.AE	6 10107	01/1994	Japan (transl. of Abstract)	C22	18	Χ .	
Aro	AF	. 6 93400	04/1994	Japan (transl. of Abstract)	C22	18	X	
Alo	AG	6 256919	09/1994	Japan (transl. of Abstract)	C22	18	x	
ALO	AH	WO 0/31310	06/2000	PCT				
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Aio	AA		C. Klein et al	., "Manual o	f Mineralogy", pp 39-40	(noda	Le)		
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APPLICANT Ritesh P. Shah

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Aro	AA	5,850,755	12/98	Segal	-	1	
Aco	- AB	5,456,815	10/95	Fukuyo et al			
Avo	AC	5,826,456	10/98	Kawazoe et al			
Aw	AD	5,413,650	05/95	Jarrett et al).	
Aro	ΑE	6,193,821	2/2001	Zhang	ĺ	1	
Aro	AF	6,348,113	02/02	Michaluk et al	J	1	
Aco	AG	6,085,966	7/00	Shimomuki et al	-	1	
Aro	АН	6,024,852	2/00	Tamura et al		1	
Aco	AI	5,798,005	8/98	Murata et al	_	-	
Aco	ĄJ	5,231,306	7/93	Meikle	-	1	
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			POREIGN PATENT DOCUMENTS				
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AM	882 813	12/1998	EPO		1	1 65	No
AN	JP 08146201A	06/1996	Japan		1		
AO	JP 10008244A	01/1998	Japan		(
AP	WO 9927150	06/1999	PCT		1		
AQ	WO 9902743	01/1999	PCT	-	1		
AR	WO 0129279	04/2001	PCT	_	_		
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Aw		AS	Mukai, T. et al, "Dynamic Mechanical Properties of a Near-Nano Aluminum Alloy Processed by Equal-Channel-Angular-Extrusion", Nano-Structured Materials, Vol. 10, No. 5, pp. 755-765 (1998) Elsevier Science Ltd.
Do		AT	Hatch, J.E., <u>ALUMINUM</u> , 1984, Chap. 5, "Metallurgy of Heat Treatment and General Principles of Precipitation Hardening", pp. 134-183.
Aro		AU	Ferrasse, S. et al., "Development of a Submicrometer-Grained Microstructure in Aluminum 6061 Using Equal Channel Angular Extrusion", J. Mater. Res. Vol. 12, No. 5, May 1997, pp. 1253-1261.
A ₁ o		AV	Ferrasse, S. et al., "Microstructure and Properties of Copper and Aluminum Alloy 3003 Heavily Worked by Equal Channel Angular Extrusion", Metallurgical and Materials Transactions A, vol. 28A, April 1997, pp. 1047-1057.
Aro		AW	Pavate et al., "Correlation between Aluminum alloy sputtering target metallurgical characteristics, Arc initiation, and In-film defect density", SPIE Vol. 3214, 1997, pp. 42-47.
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Aru	AA	3,653,981	04/1972	Watanabe et al.		148	12.4		
Aco	AB	3,849,212	11/1974	Thornburg		148	31.55		
Aw	AC	5,766,380	06/1998	Lo et al.		148	577		
Aco	AD	6,123.896	09/2000	Meeks, III et al.		419	49		
Avo	AE	5,722,165	03/1998	Kobayashi et al.		29	894.325		
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Aco	AM	08-134606	05/28/96	Japan (Abstract)		-	-	Yes X	No
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Aro	AA	5,171,379	12/1992	Kumar et al.	_	_	-	
Ara	AB	4,517,032	05/1985	Goto et al	_	_		
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